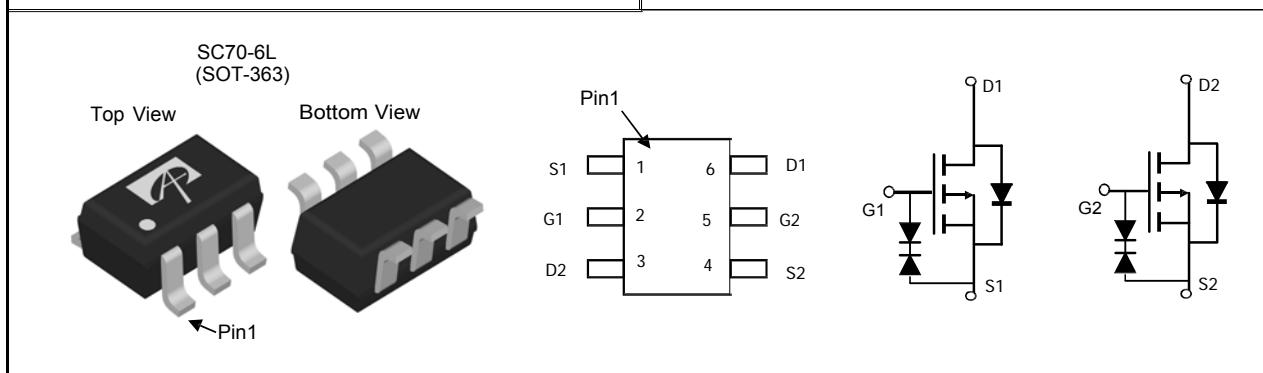


## HM2301BWKR

Dual P-Channel Enhancement Mode Field Effect Transistor

General Description	Features
<p>The HM2301BWKR uses advanced trench technology to provide excellent <math>R_{DS(ON)}</math>, low gate charge, and operation with gate voltages as low as 1.8V, in the small SOT363 footprint. It can be used for a wide variety of applications, including load switching, low current inverters and low current DC-DC converters. It is ESD protected to 2KV HBM.</p>	<p><math>V_{DS}</math> (V) = -20V  <math>I_D</math> = -0.8A (<math>V_{GS}</math> = -4.5V)</p> <p><math>R_{DS(ON)} &lt; 480\text{m}\Omega</math> (<math>V_{GS} = -4.5\text{V}</math>)  <math>R_{DS(ON)} &lt; 950\text{m}\Omega</math> (<math>V_{GS} = -2.5\text{V}</math>)  <math>R_{DS(ON)} &lt; 2200\text{m}\Omega</math> (<math>V_{GS} = -1.8\text{V}</math>)</p> 



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted			
Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current <sup>A</sup>	$I_D$	-0.8	A
$T_A=70^\circ\text{C}$		-0.56	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	-2.4	
Power Dissipation <sup>A</sup>	$P_D$	0.3	W
$T_A=70^\circ\text{C}$		0.19	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

Thermal Characteristics					
Parameter	Symbol	Typ	Max	Units	
Maximum Junction-to-Ambient <sup>A</sup>	$R_{JA}$	360	415	°C/W	
Maximum Junction-to-Ambient <sup>A</sup>		400	460	°C/W	
Maximum Junction-to-Lead <sup>C</sup>	$R_{JL}$	300	350	°C/W	

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250 \text{ A}, V_{GS}=0\text{V}$	-20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	A
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			$\pm 10$	A
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250 \text{ A}$	-0.45		-1.2	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-3			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-0.8\text{A}$ $T_J=125^\circ\text{C}$	350	480		m
		$V_{GS}=-2.5\text{V}, I_D=-0.5\text{A}$	440	670		m
		$V_{GS}=-1.8\text{V}, I_D=-0.4\text{A}$	550	950		m
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-0.8\text{A}$	780	2200		m
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-0.5\text{A}, V_{GS}=0\text{V}$	1.7		-0.86	V
$I_s$	Maximum Body-Diode Continuous Current				-1	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$	114	140		pF
$C_{\text{oss}}$	Output Capacitance		17			pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		14			pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	12	17		
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-0.8\text{A}$	1.44	1.8		nC
$Q_{\text{gs}}$	Gate Source Charge		0.14			nC
$Q_{\text{gd}}$	Gate Drain Charge		0.35			nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=16.7 \Omega, R_{\text{GEN}}=3 \Omega$	6.5			ns
$t_r$	Turn-On Rise Time		6.5			ns
$t_{\text{D(off)}}$	Turn-Off DelayTime		18.2			ns
$t_f$	Turn-Off Fall Time		5.5			ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-0.8\text{A}, dI/dt=100\text{A}/\text{s}$	10	13		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-0.8\text{A}, dI/dt=100\text{A}/\text{s}$	3			nC

A: The value of  $R_{JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

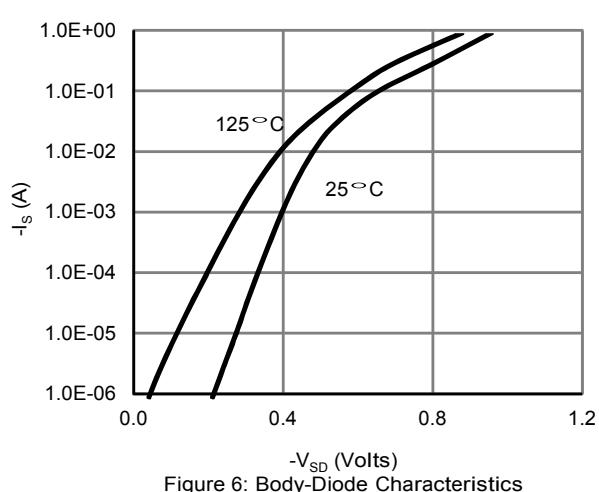
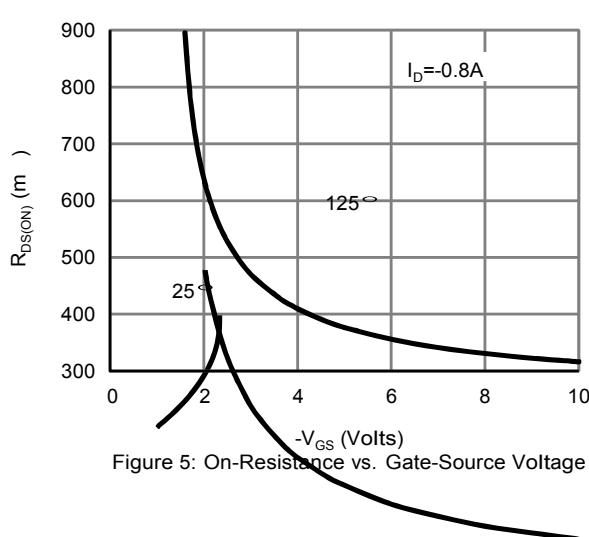
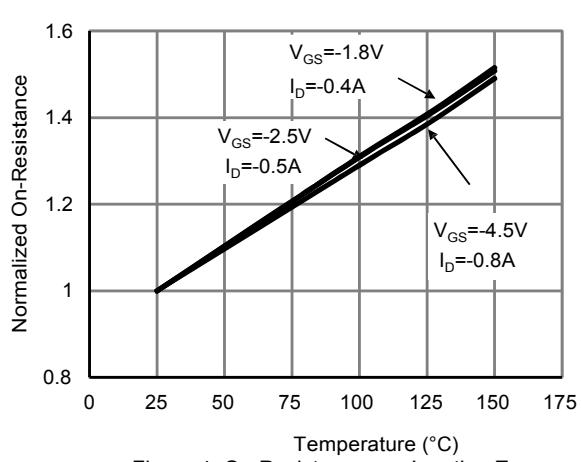
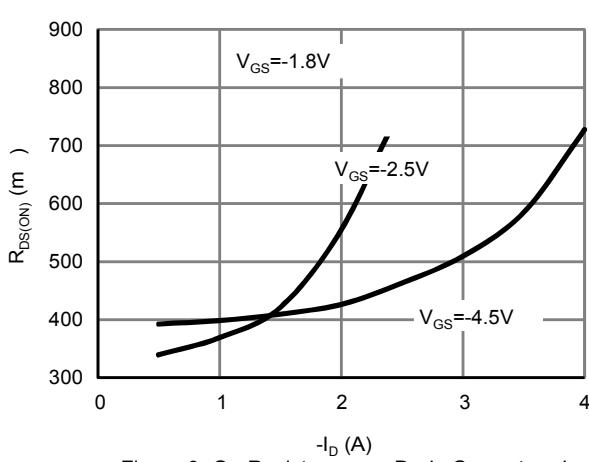
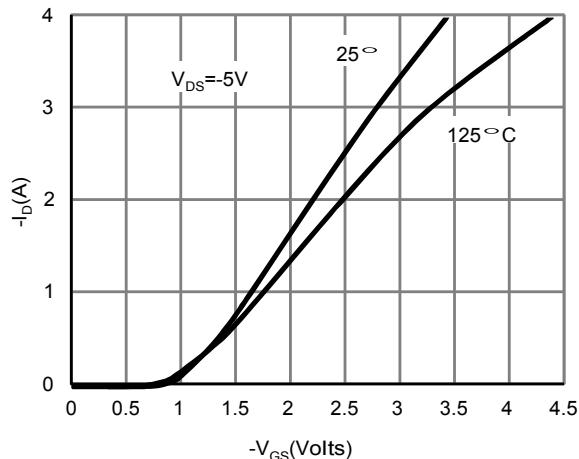
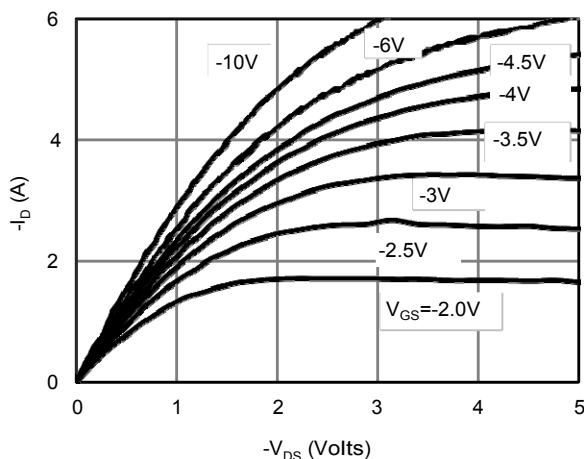
C. The  $R_{JA}$  is the sum of the thermal impedance from junction to lead  $R_{JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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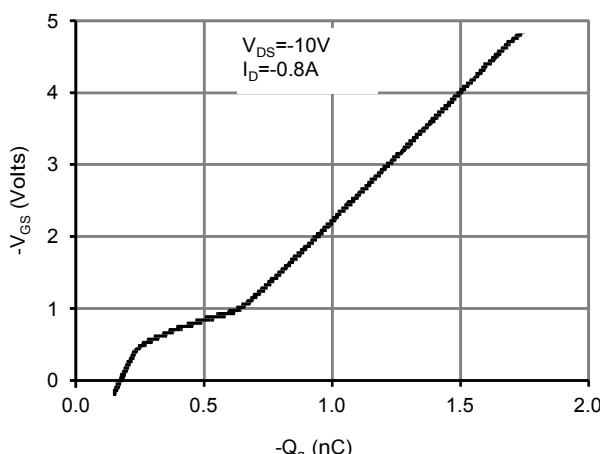


Figure 7: Gate-Charge Characteristics

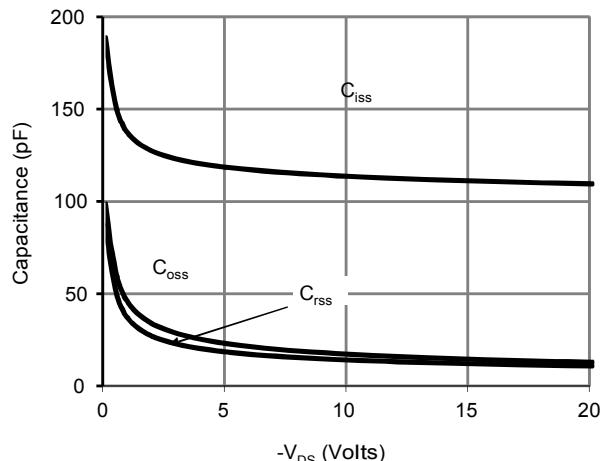


Figure 8: Capacitance Characteristics

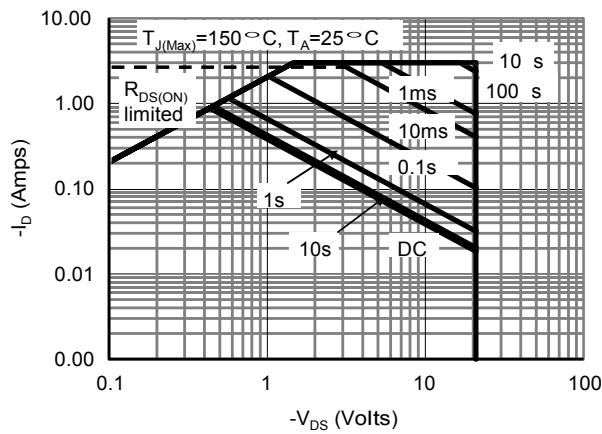


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

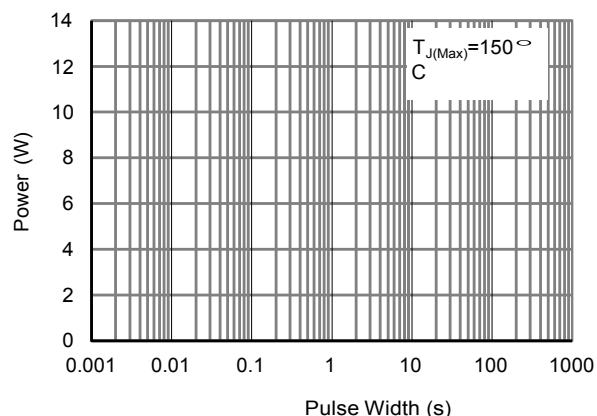


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

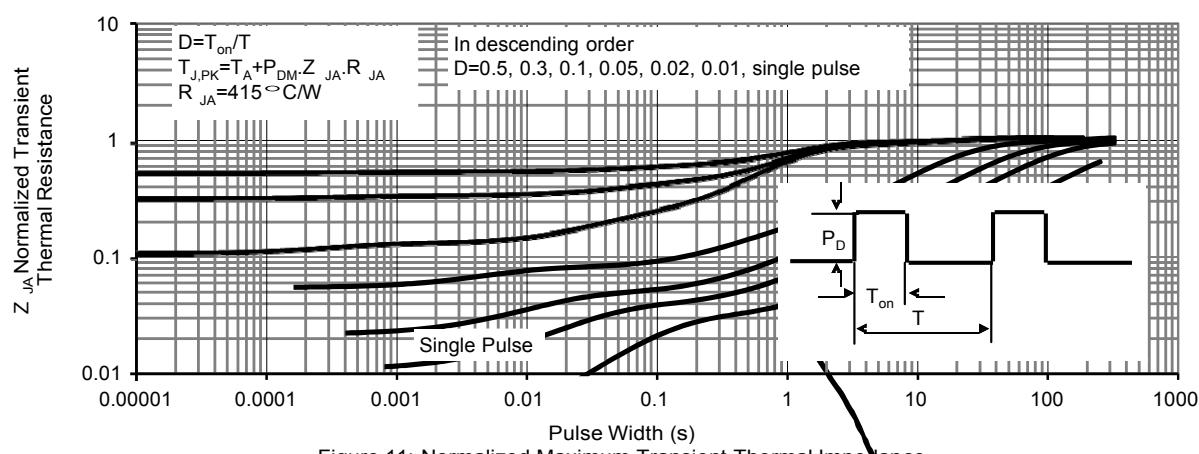
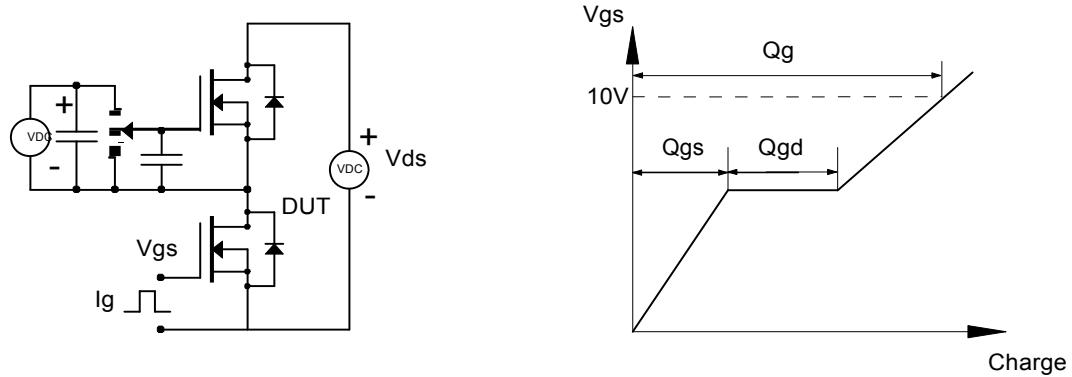
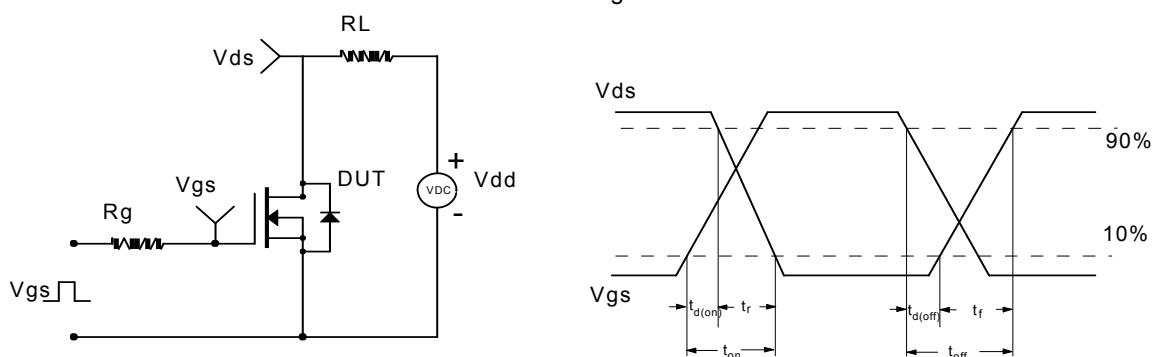


Figure 11: Normalized Maximum Transient Thermal Impedance

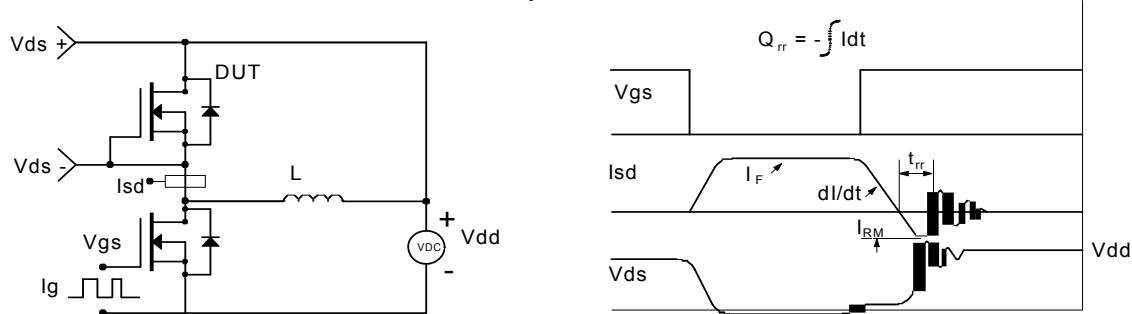
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



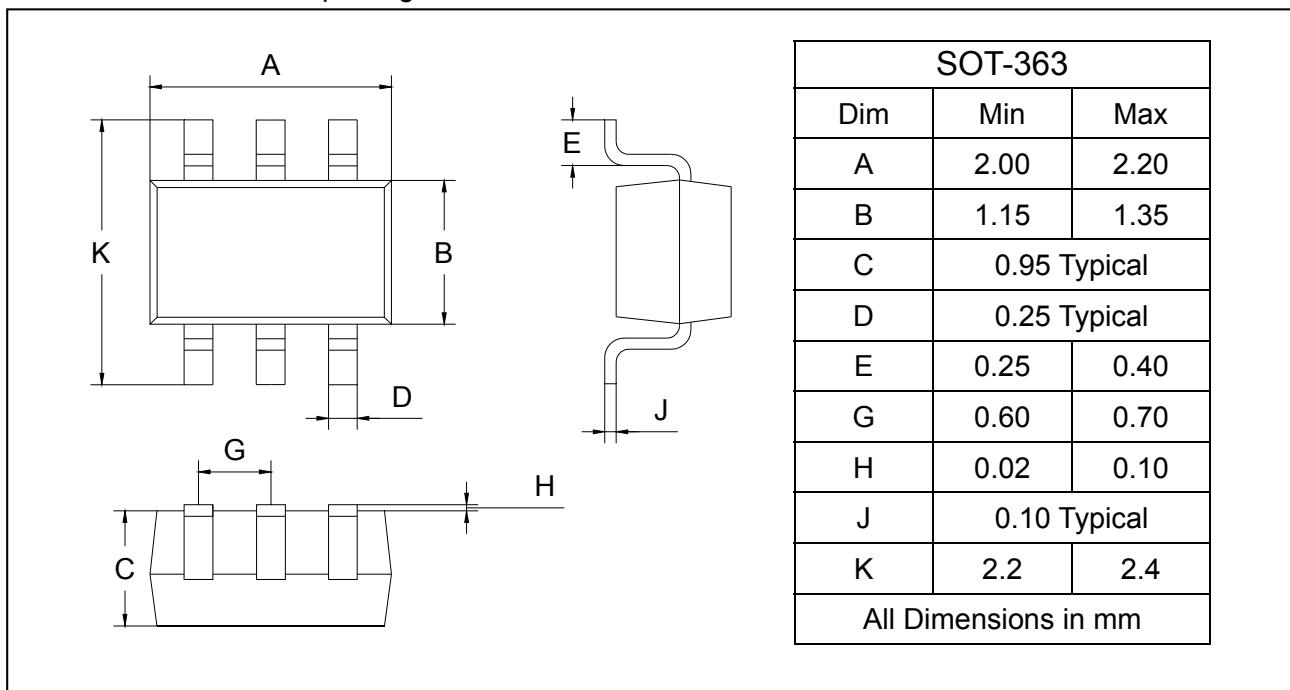
Diode Recovery Test Circuit & Waveforms



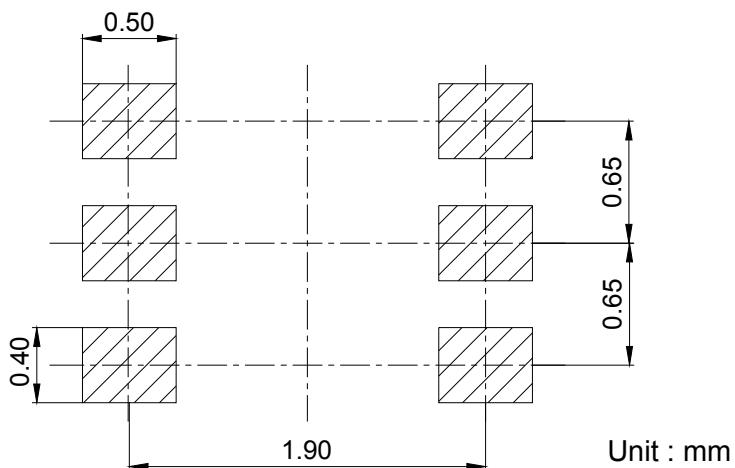
## PACKAGE OUTLINE

Plastic surface mounted package

SOT-363



## SOLDERING FOOTPRINT



## PACKAGE INFORMATION

Device	Package	Shipping
HM2301BWKR	SOT-363	3000/Tape&Reel